Form PTO-1449 U.S. Dept. of Commerce Patent & Trademark Office	Atty. Docket: 01-S-020	Serial No. 09/993,970
List of Documents Cited by Applicant (Use several sheets if necessary)	Applicant: Peter J. McGUINNESS et al.	
	Filing Date: November 16, 2001	Group: 2621

MAR 2 5 2002

U.S. PATENT DOCUMENTS

Exmr In'l	Document Number	Date	Name	Class	Sub-class	Filing Date, if applicable

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub-class	Transl'n Yes/No
dR	AA1	GB 2,272,285	May 11, 1994	UK	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

dR	AA2	R. Deriche et al., "Robust Recovery of the Epipolar Geometry for an Uncalibrated Stereo Rig", Proceedings of the European Conference on Computer Vision, pages 567-576, Stockholm, Sweden, May 1994, Springer-Verlag, SNCS 800.
dR	AA3	Z. Zhang et al., "A Robust Technique for Matching Two Uncalibrated Images Through the Recovery of the Unknown Epipolar Geometry", Artificial Intelligence Journal Vol. 78, pages 87-119, October 1995
dR	AA4	T. Kanade, "A Stereo Machine for Video-Rate Dense Depth Mapping and Its new Applications, School of Computer Science, Carnegie Mellon University, IEEE Conf. Computer Vision and Pattern Recognition, 1996.
dR	AA5	P.H.S. Torr et al., "Robust Parameterization and Computation of the Trifocal Tensor", Image and Vision Computing, 1997.
dR	AA6	M. Pollefeys et al., "Self-Calibration and Metric Reconstruction in spite of Varying and Unknown Internal Camera Parameters, IEEE International Conf. Computer Vision, 1998
dR	AA7	K. Ng, "3D Visual Modeling and Virtual View Synthesis: A Synergetic, Range-Space Stereo Approach Using Omni-Directional Images," Ph.D. Dissertation, University of California, San Diego, March 2000
dR	AA8	Kim C. Ng et al., "Range-Space Approach for Generalized Multiple Baseline Stereo and Direct Virtual View Synthesis", IEEE Workshop on Stereo and Multiple-Baseline Vision, December 9-10, 2001
dR	AA9	George Q. Chen, "Robust Point Feature Matching In Projective Space", IEEE Computer Vision and Pattern Recognition 2001.
		RECEIVED
		MAR 2 9 2002
		Technology Center 2600

Examiner:	Date Considered: 11- 16, 04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

IDS&1449.wpd